

10/659,626



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PATENT

In re Patent Application of

Jon Opsal et al.

Application No.: 10/659,626

Filed: September 10, 2003

For: MODULATED REFLECTANCE
MEASUREMENT SYSTEM USING
UV PROBE

Confirmation No.: 5574

Group Art Unit: 2877

Examiner: Layla G. Lauchman

**RESPONSE TO OFFICE ACTION
MAILED FEBRUARY 24, 2006**

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M/S AMENDMENT
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited
with the United States Postal Service as First Class Mail in an
envelope, addressed to: Commissioner for Patents, P.O.
Box 1450, Alexandria, VA 22313-1450 on March 31, 2006.

STALLMAN & POLLOCK LLP

Dated: 03/31/2006

By:

Georgia K. Stith

Sir:

In response to the Office Action mailed February 24, 2006, please amend the above-identified application as follows:

Amendment to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks begin on page 6 of this paper.

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100.00 DP

Atty Docket No.: TWI-23010